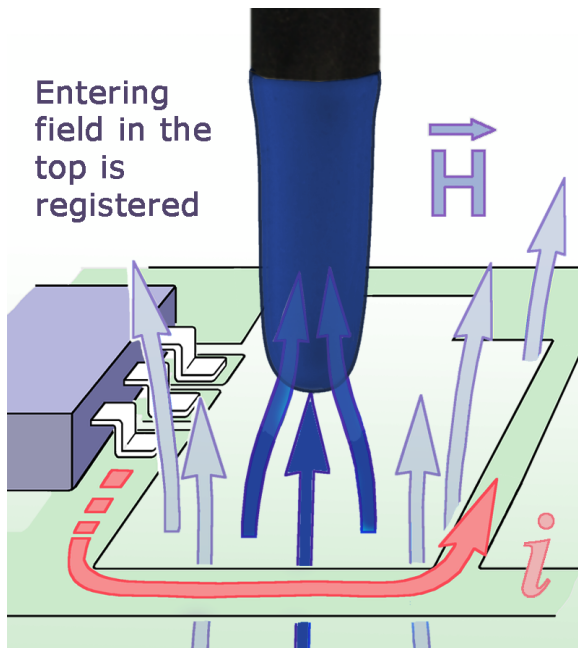


LFS-B 3

磁场探头 (100KHz-50MHz) SMA



Short description

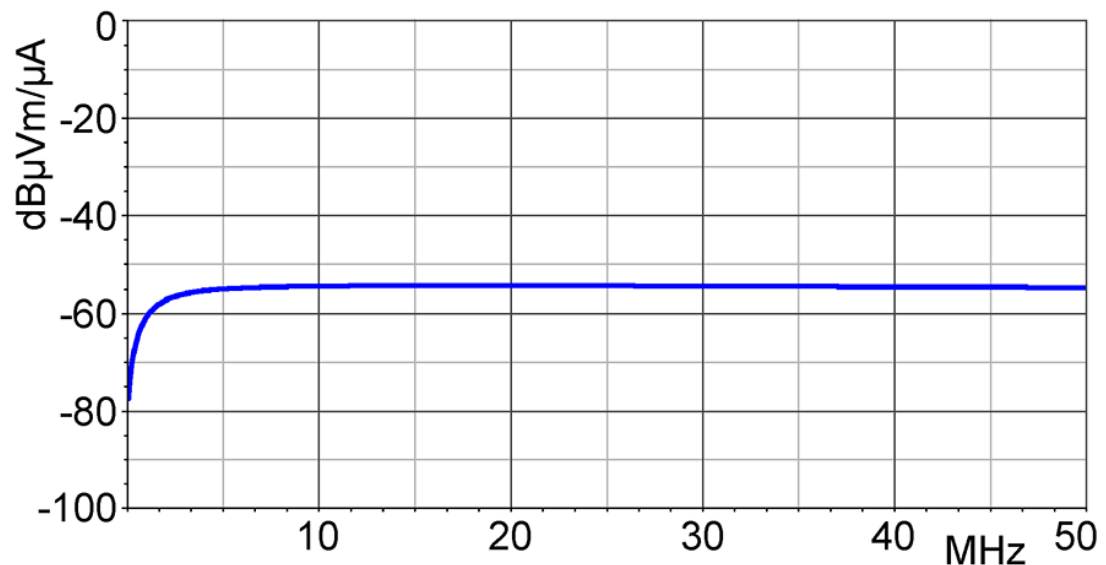
LF-B3型磁场探头的测量线圈相对垂直于探头柄。当探头竖直放置电路板上时，其测量线圈直接平放在电路板的表面上。由此就能够测量到印刷电路板表面上很难达到的一些位置，如开关调节器的大元件之间的位置。

The LFS-B 3 is a passive near-field probe for use in a scanner to measure magnetic field during development. The LFS-B 3 detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected. The near-field probe is small and handy. It has a current attenuating sheath and is, therefore, electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω.

Technical parameters

频率范围	100 kHz ... 50 MHz
分辨率	≈ 2 mm
探头尺寸	Ø ≈ 4 mm
输出接口	SMA, male, jack

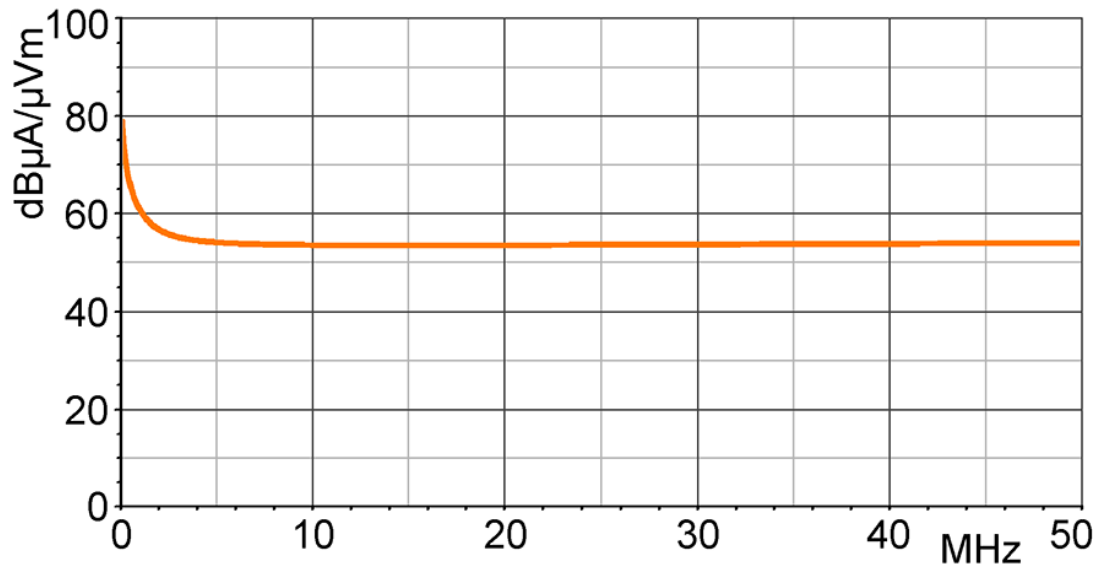
频率特性 [dBμV] / [dBμA/m]



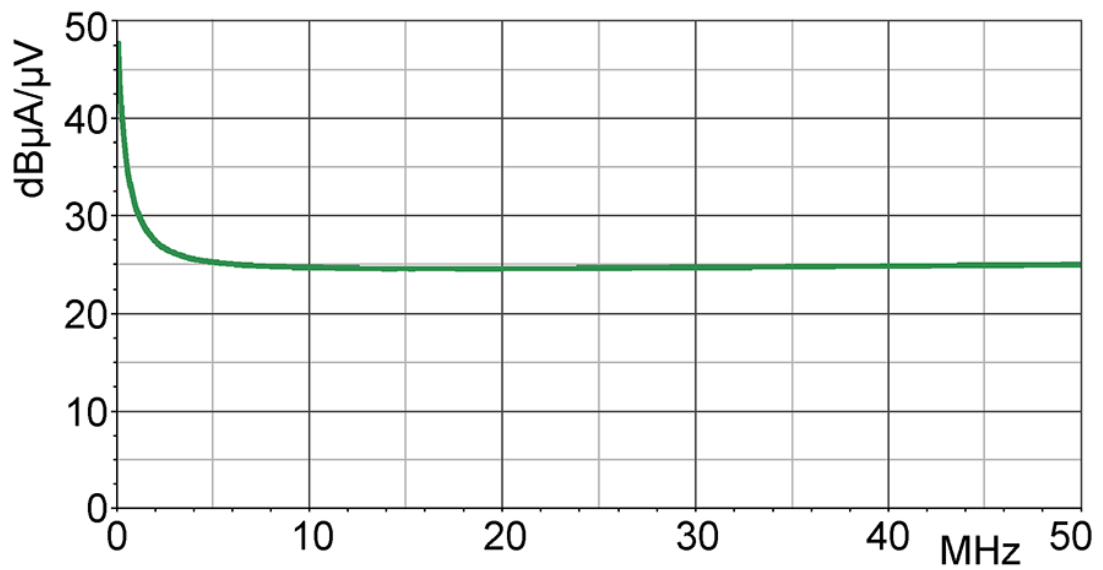
LFS-B 3

磁场探头 (100KHz-50MHz) SMA

磁场校正曲线 [dB μ A/m] / [dB μ V]

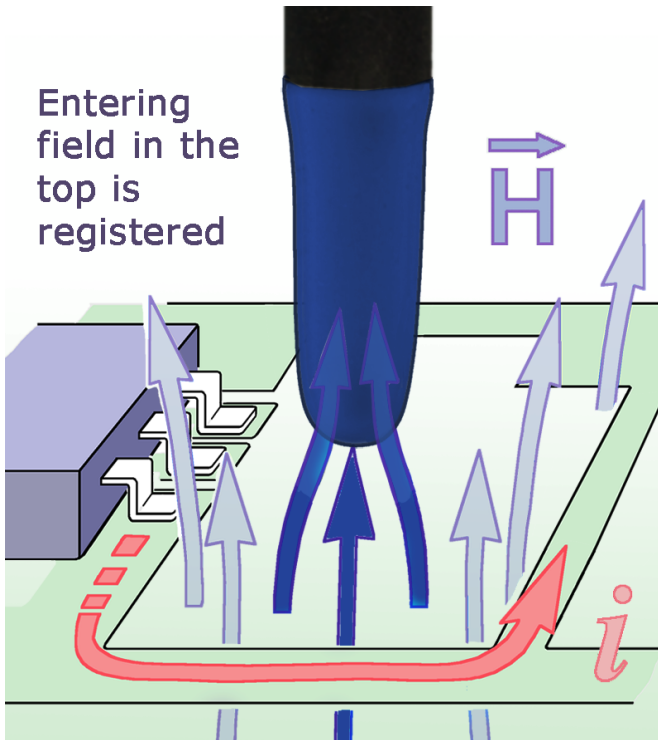


电流校正曲线 [dB μ A] / [dB μ V]



LFS-B 3

磁场探头 (100KHz-50MHz) SMA



LFS-B 3

磁场探头 (100KHz-50MHz) SMA

LFS-B 3-2 scanner probe connected to ICS 105 scanner

